

FEATURES

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DESCRIPTION

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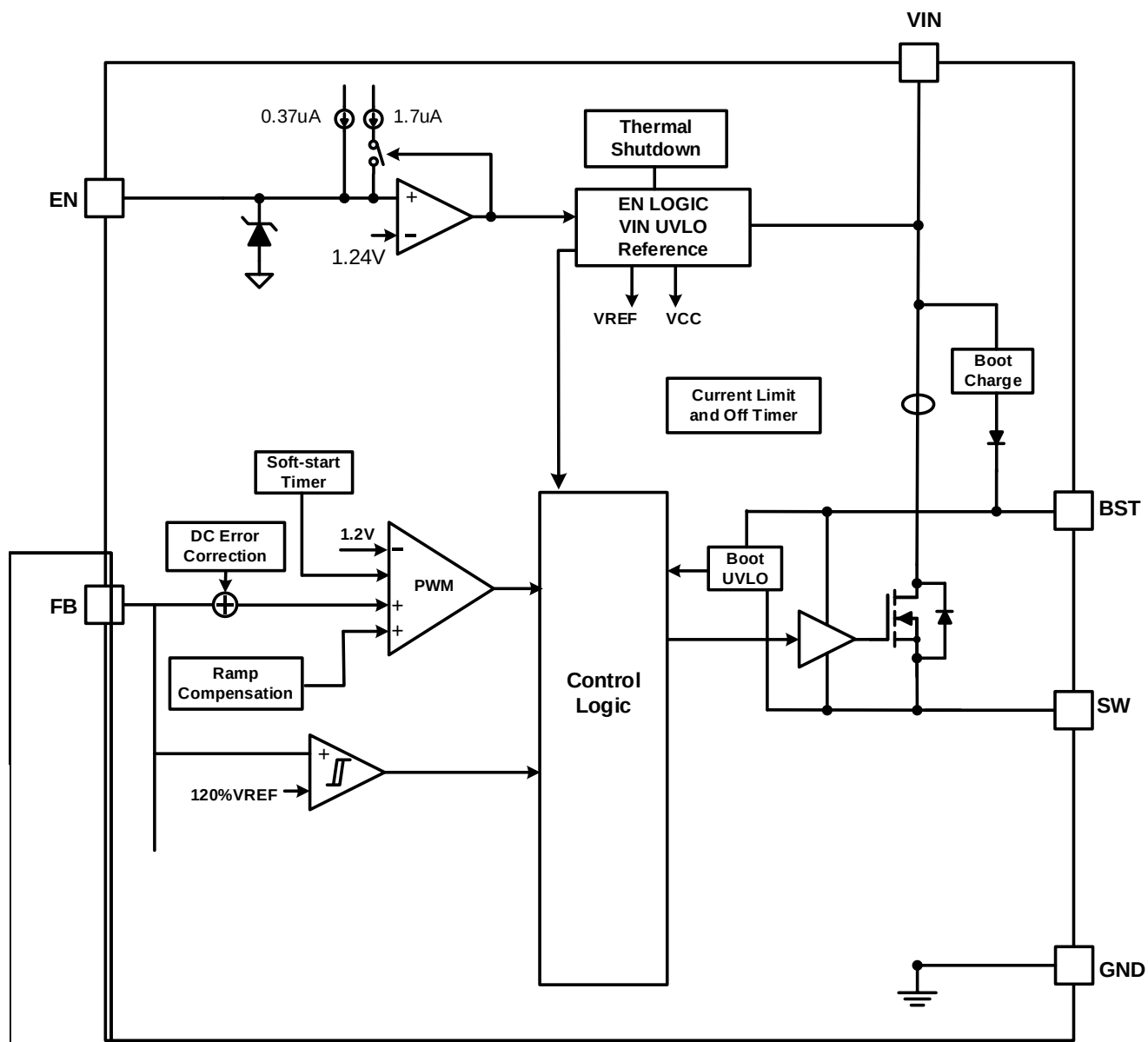
APPLICATIONS

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REVISION HISTORY

DEVICE ORDER INFORMATION

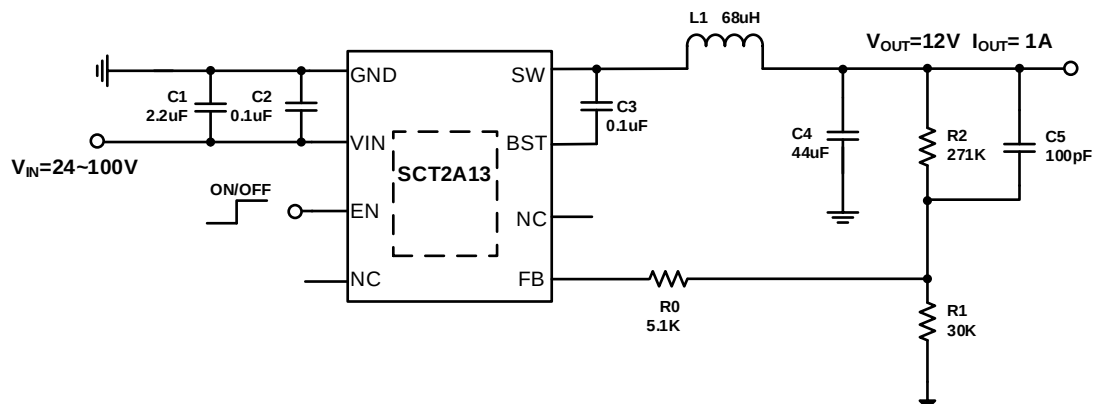
FUNCTIONAL BLOCK DIAGRAM





OPERATION

APPLICATION INFORMATION

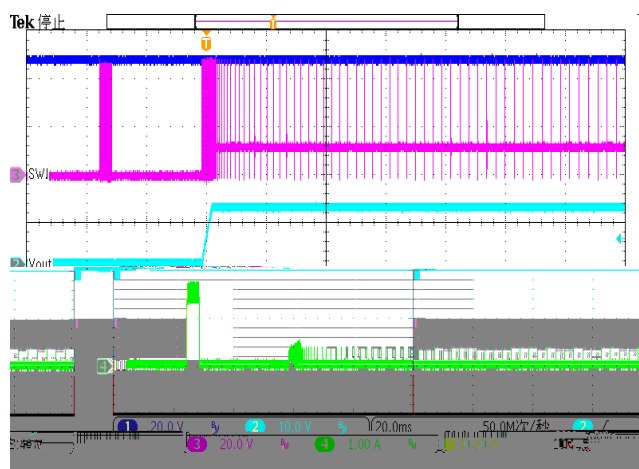
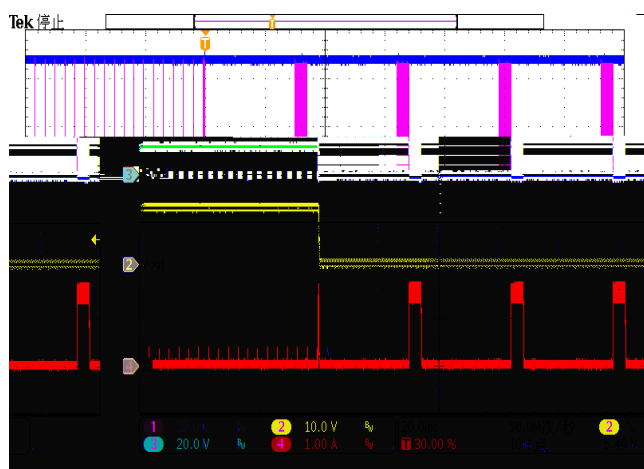
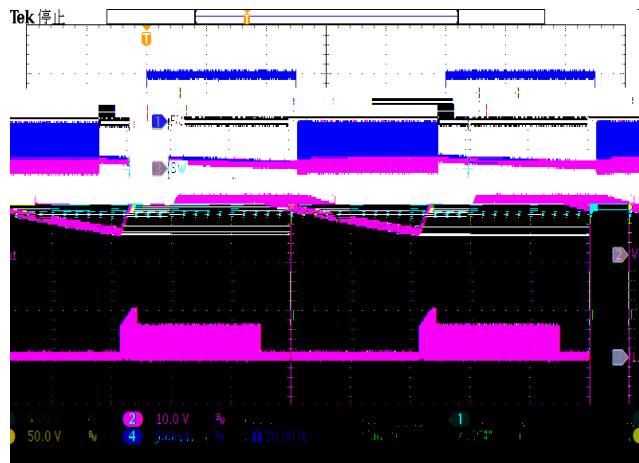
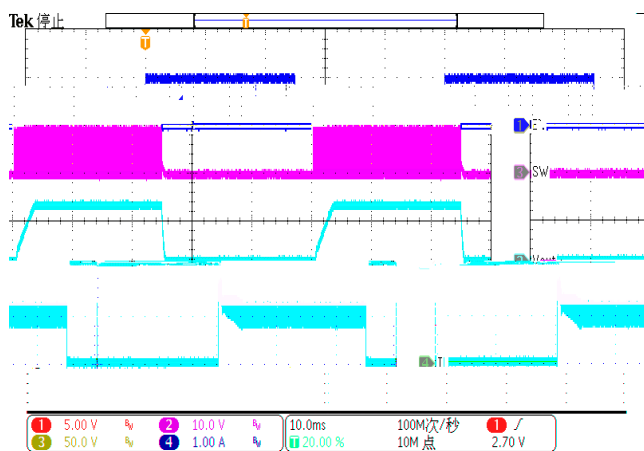
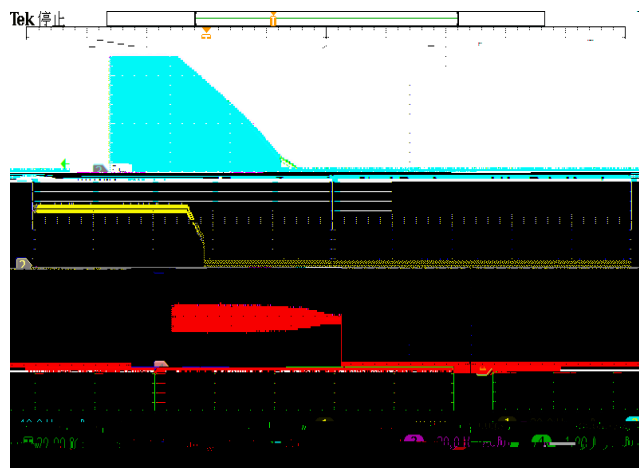
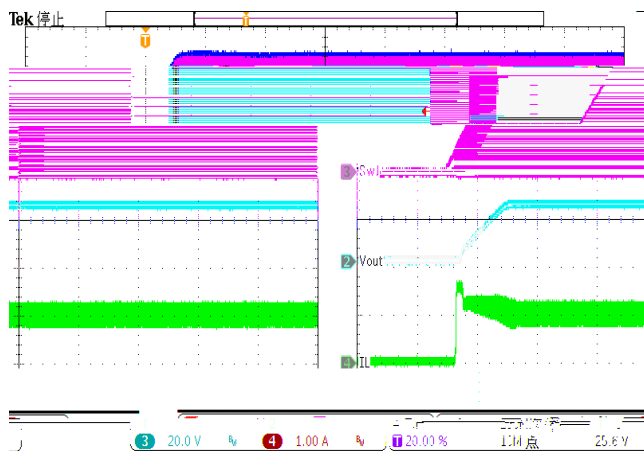


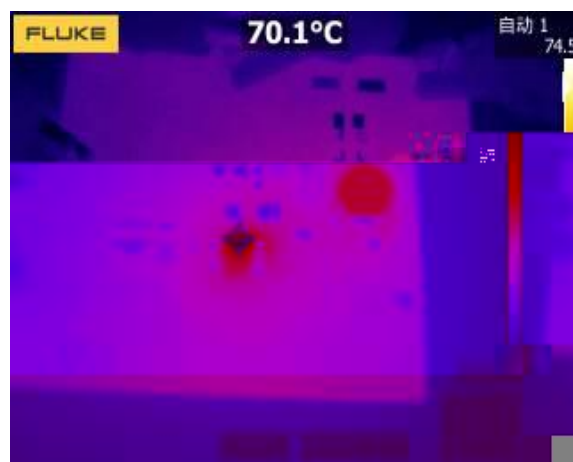
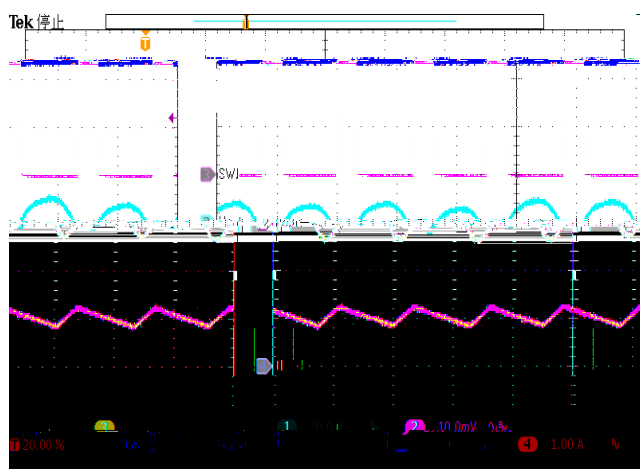
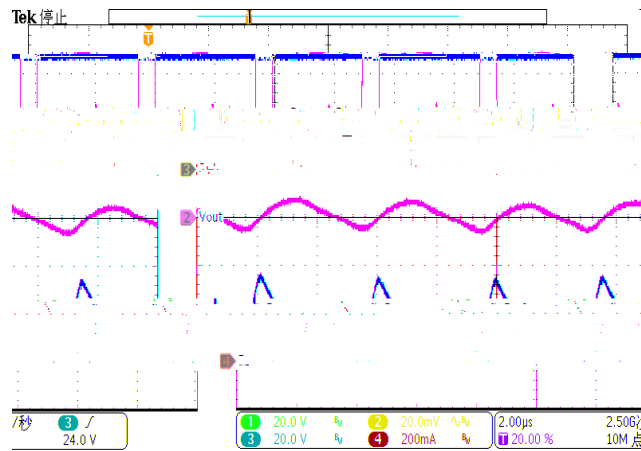
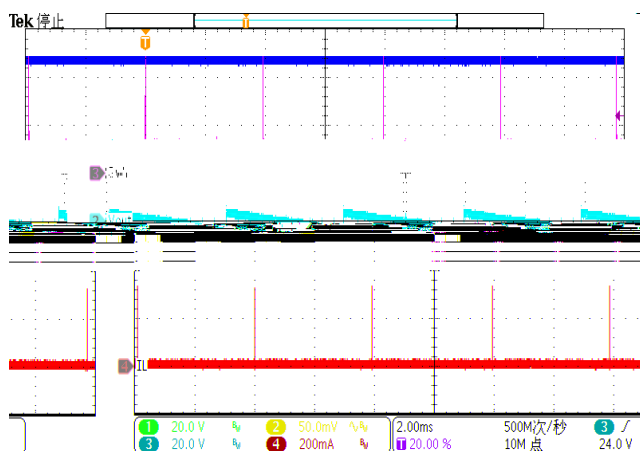
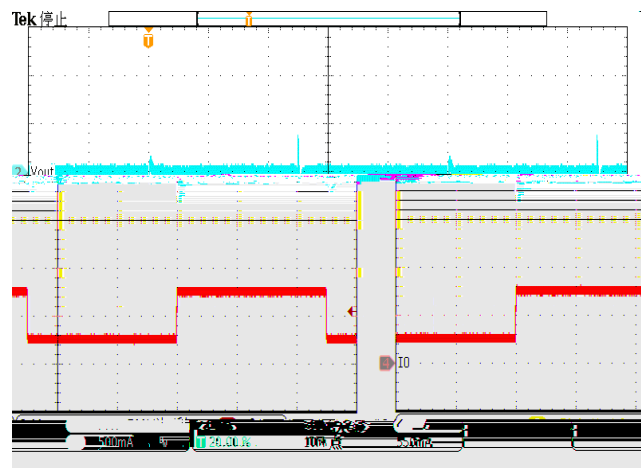
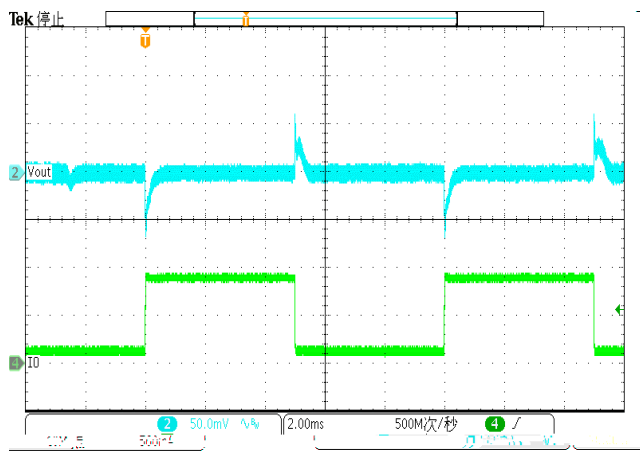
$$_2 = ($$

$$I_{CINRMS} = I_{OUT} \sqrt{\frac{V_{OUT}}{V_{IN}} \left(1 - \frac{V_{OUT}}{V_{IN}}\right)}$$

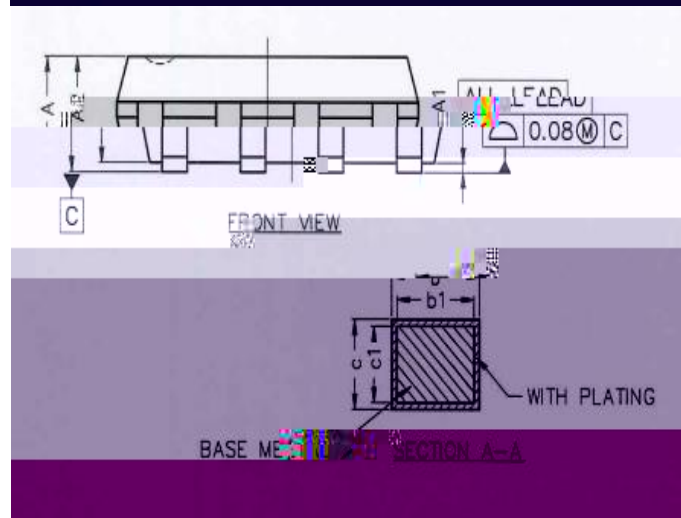
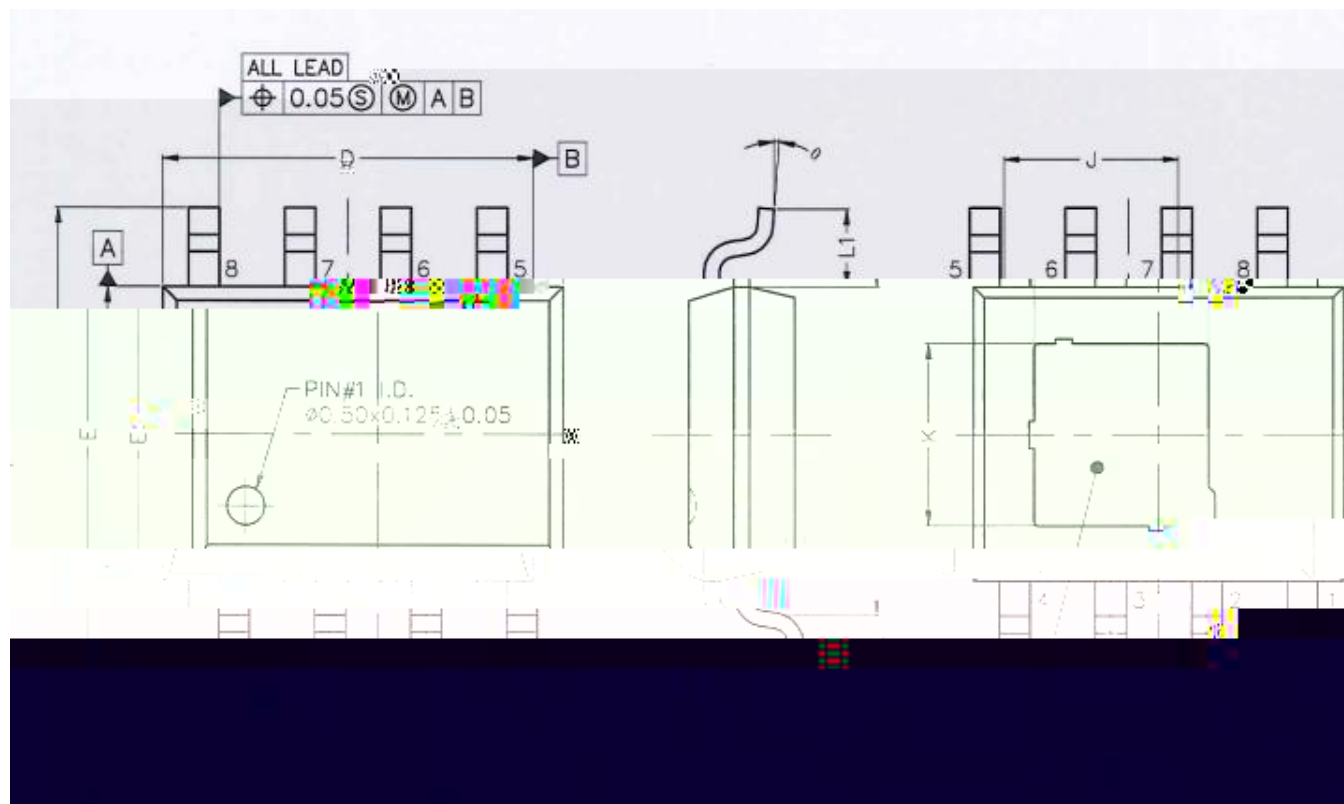
$$I_{CINRMS} = 0.5 I_{OUT}$$

$$\Delta V_{IN} = \frac{I_{OUT}}{f_{SW} C_{IN}} \frac{V_{OUT}}{V_{IN}}$$





PACKAGE INFORMATION



	SYMBOL	MIN	NOM	MAX	
TOTAL THICKNESS	A	—	—	1.75	
STAND OFF	A1	0.05	0.125	0.20	
MOLD TOTAL THICKNESS	A2	1.30	1.40	1.60	
LEAD WIDTH	b	0.31		0.53	
LEAD WIDTH	b1	0.30	0.40	0.50	
LEAD THICKNESS	c	0.20		0.24	
LEAD THICKNESS	c1	0.19	0.203	0.21	
MOLD LENGTH	D	4.80	4.90	5.00	
MOLD WIDTH	E1	3.80	3.90	4.00	
LEAD SPAN	E	5.80	6.00	6.20	
LEAD PITCH	F	1.27	1.27	1.27	
EXPOSED PAD SIZE	X	J	2.15	2.30	2.4
	Y	K	2.25	2.40	2.5
LEAD LENGTH	L1		1.05	REF	
LEAD SOLE LENGTH	L		0.40	0.60	0.8
LEAD FORM ANGLE	θ		0°	—	8°

The diagram illustrates the experimental setup for measuring the time delay of a quantum state. It features a laser source at the top left, which emits a beam that passes through a beam splitter. The beam is then directed through a delay line, which is represented by a series of parallel lines. The beam is then reflected by another beam splitter and directed towards a detector at the bottom right. The diagram also shows the path of a quantum state, which is represented by a series of parallel lines. The time delay is measured by comparing the time taken for the quantum state to reach the detector with the time taken for the beam to reach the detector.

